AMENDMENTS TO THE CLAIMS

- 1-50. (Canceled)
- 51. (New) A microbattery, comprising:
 - a substrate;
- a conductive layer comprising a metal element formed directly on a surface of the substrate;
- a thin-film cathodic layer comprising a sulfide of the metal element electrochemically formed directly on the conductive layer;
- a thin-film electrolyte layer formed directly on the cathodic layer; and
- a thin-film anodic layer formed directly on the electrolyte layer.
- 52. (New) The microbattery according to claim 51, wherein the metal element is copper, and the cathodic layer comprises copper sulfide electrooxidized onto the copper.
- 53. (New) The microbattery according to claim 51, wherein the cathodic layer has a thickness between 1 and 3 μm .
- 54. (New) The microbattery according to claim 51, wherein the substrate comprises a semiconductor material.
- 55. (New) The microbattery according to claim 51, wherein the substrate has a plurality of cavities, and wherein the conductive and thin film layers are formed on an inner surface of the cavities.
- 56. (New) A microbattery, comprising:
- a semiconductor substrate having a plurality of cavities;
- a conductive layer formed directly on a surface of the substrate including an inner surface of the cavities;
- a thin-film cathodic layer formed directly on the conductive layer;

- a thin-film electrolyte layer formed directly on the cathodic layer; and
- a thin-film anodic layer formed directly on the electrolyte layer.